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Sommario/riassunto

Handbook of Microwave Component Measurements Second Edition is a fully updated, complete reference to this topic, focusing on the modern measurement tools, such as a Vector Network Analyzer (VNA), gathering in one place all the concepts, formulas, and best practices of measurement science. It includes basic concepts in each chapter as well as appendices which provide all the detail needed to understand the science behind microwave measurements. The book offers an insight into the best practices for ascertaining the true nature of the device-under-test (DUT), optimizing the time to setup and measure, and to the greatest extent possible, remove the effects of the measuring equipment from that result. Furthermore, the author writes with a simplicity that is easily accessible to the student or new engineer, yet is thorough enough to provide details of measurement science for even the most advanced applications and researchers. This welcome new edition brings forward the most modern techniques used in industry today, and recognizes that more new techniques have developed since the first edition published in 2012. Whilst still focusing on the VNA, these techniques are also compatible with other vendor's advanced equipment, providing a comprehensive industry reference.

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	-- The Christian just-war tradition -- Underlying convictions of just-war thinking -- Just-war criteria -- Strengths and weaknesses of Christian just-war thinking -- What can we do? -- General observations -- Some responses Christians can make -- Afterword -- The present international situation -- Some implications for moral reflection about war.
Sommario/riassunto	War: A Primer for Christians provides a concise introduction to the main approaches that Christians have taken toward war and examines each approach critically. Some Christians have supported their country's wars as crusades of good against evil. Others, as pacifists, have rejected participation in or support for any war. Still others have followed the just-war tradition in holding that it can be justifiable under some conditions to resort to war, but that then Christian love must limit the conduct of war.In an updated preface and new afterword, Allen explores aspects of current internationa